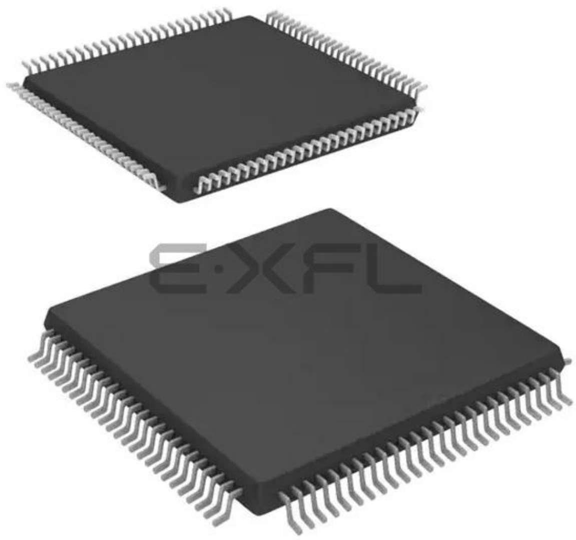
Silicon Labs - EFM32GG11B520F2048GQ100-AR Datasheet



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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, EBI/EMI, I²C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, LCD, POR, PWM, WDT
Number of I/O	83
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 16x12b SAR; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32gg11b520f2048gq100-ar

Email: info@E-XFL.COM
Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

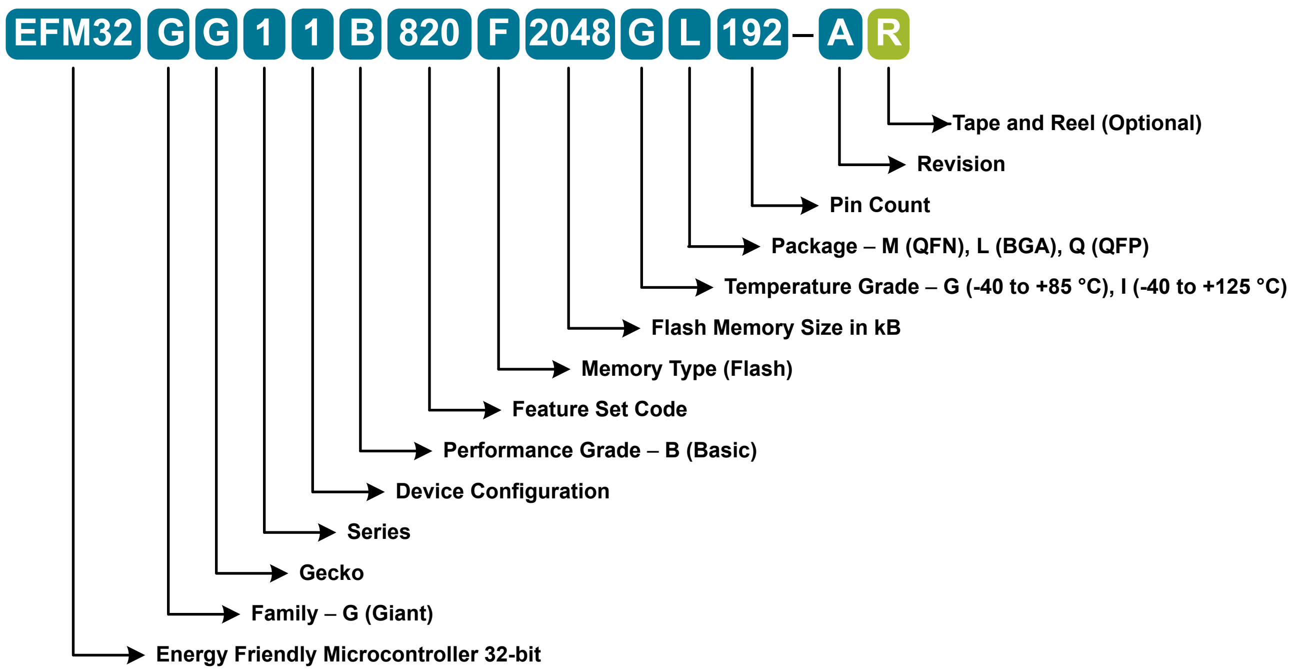

Figure 2.1. Ordering Code Key

3.8.4 Capacitive Sense (CSEN)

The CSEN module is a dedicated Capacitive Sensing block for implementing touch-sensitive user interface elements such a switches and sliders. The CSEN module uses a charge ramping measurement technique, which provides robust sensing even in adverse conditions including radiated noise and moisture. The module can be configured to take measurements on a single port pin or scan through multiple pins and store results to memory through DMA. Several channels can also be shorted together to measure the combined capacitance or implement wake-on-touch from very low energy modes. Hardware includes a digital accumulator and an averaging filter, as well as digital threshold comparators to reduce software overhead.

3.8.5 Digital to Analog Current Converter (IDAC)

The Digital to Analog Current Converter can source or sink a configurable constant current. This current can be driven on an output pin or routed to the selected ADC input pin for capacitive sensing. The full-scale current is programmable between 0.05 µA and 64 µA with several ranges consisting of various step sizes.

3.8.6 Digital to Analog Converter (VDAC)

The Digital to Analog Converter (VDAC) can convert a digital value to an analog output voltage. The VDAC is a fully differential, 500 ksps, 12-bit converter. The opamps are used in conjunction with the VDAC, to provide output buffering. One opamp is used per single-ended channel, or two opamps are used to provide differential outputs. The VDAC may be used for a number of different applications such as sensor interfaces or sound output. The VDAC can generate high-resolution analog signals while the MCU is operating at low frequencies and with low total power consumption. Using DMA and a timer, the VDAC can be used to generate waveforms without any CPU intervention. The VDAC is available in all energy modes down to and including EM3.

3.8.7 Operational Amplifiers

The opamps are low power amplifiers with a high degree of flexibility targeting a wide variety of standard opamp application areas, and are available down to EM3. With flexible built-in programming for gain and interconnection they can be configured to support multiple common opamp functions. All pins are also available externally for filter configurations. Each opamp has a rail to rail input and a rail to rail output. They can be used in conjunction with the VDAC module or in stand-alone configurations. The opamps save energy, PCB space, and cost as compared with standalone opamps because they are integrated on-chip.

3.8.8 Liquid Crystal Display Driver (LCD)

The LCD driver is capable of driving a segmented LCD display with up to 8x36 segments. A voltage boost function enables it to provide the LCD display with higher voltage than the supply voltage for the device. A patented charge redistribution driver can reduce the LCD module supply current by up to 40%. In addition, an animation feature can run custom animations on the LCD display without any CPU intervention. The LCD driver can also remain active even in Energy Mode 2 and provides a Frame Counter interrupt that can wake-up the device on a regular basis for updating data.

3.9 Reset Management Unit (RMU)

The RMU is responsible for handling reset of the EFM32GG11. A wide range of reset sources are available, including several power supply monitors, pin reset, software controlled reset, core lockup reset, and watchdog reset.

3.10 Core and Memory

3.10.1 Processor Core

The ARM Cortex-M processor includes a 32-bit RISC processor integrating the following features and tasks in the system:

- ARM Cortex-M4 RISC processor with FPU achieving 1.25 Dhrystone MIPS/MHz
- Memory Protection Unit (MPU) supporting up to 8 memory segments
- Embedded Trace Macrocell (ETM) for real-time trace and debug
- Up to 2048 kB flash program memory
  - Dual-bank memory with read-while-write support
- Up to 512 kB RAM data memory
- Configuration and event handling of all modules
- 2-pin Serial-Wire or 4-pin JTAG debug interface

4.1.10.2 High-Frequency Crystal Oscillator (HFXO)

Table 4.13. High-Frequency Crystal Oscillator (HFXO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal frequency	f_{HFXO}	No clock doubling	4	—	50	MHz
		Clock doubler enabled	TBD	—	TBD	MHz
Supported crystal equivalent series resistance (ESR)	ESR_{HFXO}	50 MHz crystal	—	—	50	Ω
		24 MHz crystal	—	—	150	Ω
		4 MHz crystal	—	—	180	Ω
Nominal on-chip tuning cap range[1]	C_{HFXO_T}	On each of HFXTAL_N and HFXTAL_P pins	8.7	—	51.7	pF
On-chip tuning capacitance step	SS_{HFXO}		—	0.084	—	pF
Startup time	t_{HFXO}	50 MHz crystal, ESR = 50 Ohm, C_L = 8 pF	—	350	—	µs
		24 MHz crystal, ESR = 150 Ohm, C_L = 6 pF	—	700	—	µs
		4 MHz crystal, ESR = 180 Ohm, C_L = 18 pF	—	3	—	ms
Current consumption after startup	I_{HFXO}	50 MHz crystal	—	880	—	µA
		24 MHz crystal	—	420	—	µA
		4 MHz crystal	—	80	—	µA

Note:

1. The effective load capacitance seen by the crystal will be C_{HFXO_T} /2. This is because each XTAL pin has a tuning cap and the two caps will be seen in series by the crystal.

4.1.10.6 USB High-Frequency RC Oscillator (USHFRCO)

Table 4.17. USB High-Frequency RC Oscillator (USHFRCO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Frequency accuracy	$f_{USHFRCO\_ACC}$	At production calibrated frequencies, across supply voltage and temperature	TBD	—	TBD	%
		USB clock recovery enabled, Active connection as device, FINETUNINGEN[1] = 1	-0.25	—	0.25	%
Start-up time	$t_{USHFRCO}$		—	300	—	ns
Current consumption on all supplies	$I_{USHFRCO}$	$f_{USHFRCO}$ = 48 MHz, FINETUNINGEN[1] = 1	—	340	TBD	μA
		$f_{USHFRCO}$ = 50 MHz, FINETUNINGEN[1] = 0	—	342	TBD	μA
		$f_{USHFRCO}$ = 48 MHz, FINETUNINGEN[1] = 0	—	292	TBD	μA
		$f_{USHFRCO}$ = 32 MHz, FINETUNINGEN[1] = 0	—	223	TBD	μA
		$f_{USHFRCO}$ = 16 MHz, FINETUNINGEN[1] = 0	—	132	TBD	μA
Period jitter	$PJ_{USHFRCO}$		—	0.2	—	% RMS

Note:

1. In the CMU_USHFRCOCTRL register.

4.1.10.7 Ultra-low Frequency RC Oscillator (ULFRCO)

Table 4.18. Ultra-low Frequency RC Oscillator (ULFRCO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Oscillation frequency	f_{ULFRCO}		TBD	1	TBD	kHz

4.1.17 Current Digital to Analog Converter (IDAC)

Table 4.25. Current Digital to Analog Converter (IDAC)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Number of ranges	N_{IDAC_RANGES}		—	4	—	ranges
Output current	I_{IDAC_OUT}	RANGSEL[1] = RANGE0	0.05	—	1.6	µA
		RANGSEL[1] = RANGE1	1.6	—	4.7	µA
		RANGSEL[1] = RANGE2	0.5	—	16	µA
		RANGSEL[1] = RANGE3	2	—	64	µA
Linear steps within each range	N_{IDAC_STEPS}		—	32	—	steps
Step size	SS_{IDAC}	RANGSEL[1] = RANGE0	—	50	—	nA
		RANGSEL[1] = RANGE1	—	100	—	nA
		RANGSEL[1] = RANGE2	—	500	—	nA
		RANGSEL[1] = RANGE3	—	2	—	µA
Total accuracy, STEPSEL[1] = 0x10	ACC_{IDAC}	EM0 or EM1, AVDD=3.3 V, T = 25 °C	TBD	—	TBD	%
		EM0 or EM1, Across operating temperature range	TBD	—	TBD	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE0, AVDD=3.3 V, T = 25 °C	—	-2.7	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE1, AVDD=3.3 V, T = 25 °C	—	-2.5	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE2, AVDD=3.3 V, T = 25 °C	—	-1.5	—	%
		EM2 or EM3, Source mode, RANGSEL[1] = RANGE3, AVDD=3.3 V, T = 25 °C	—	-1.0	—	%
		EM2 or EM3, Sink mode, RANG-SEL[1] = RANGE0, AVDD=3.3 V, T = 25 °C	—	-1.1	—	%
		EM2 or EM3, Sink mode, RANG-SEL[1] = RANGE1, AVDD=3.3 V, T = 25 °C	—	-1.1	—	%
		EM2 or EM3, Sink mode, RANG-SEL[1] = RANGE2, AVDD=3.3 V, T = 25 °C	—	-0.9	—	%
		EM2 or EM3, Sink mode, RANG-SEL[1] = RANGE3, AVDD=3.3 V, T = 25 °C	—	-0.9	—	%

4.1.18 Capacitive Sense (CSEN)

Table 4.26. Capacitive Sense (CSEN)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Single conversion time (1x accumulation)	t_{CNV}	12-bit SAR Conversions	—	20.2	—	µs
		16-bit SAR Conversions	—	26.4	—	µs
		Delta Modulation Conversion (single comparison)	—	1.55	—	µs
Maximum external capacitive load	C_{EXTMAX}	CS0CG=7 (Gain = 1x), including routing parasitics	—	68	—	pF
		CS0CG=0 (Gain = 10x), including routing parasitics	—	680	—	pF
Maximum external series impedance	R_{EXTMAX}		—	1	—	kΩ
Supply current, EM2 bonded conversions, WARMUP-MODE=NORMAL, WARMUPCNT=0	I_{CSEN_BOND}	12-bit SAR conversions, 20 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	326	—	nA
		Delta Modulation conversions, 20 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	226	—	nA
		12-bit SAR conversions, 200 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	33	—	nA
		Delta Modulation conversions, 200 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	25	—	nA
Supply current, EM2 scan conversions, WARMUP-MODE=NORMAL, WARMUPCNT=0	I_{CSEN_EM2}	12-bit SAR conversions, 20 ms scan rate, CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	690	—	nA
		Delta Modulation conversions, 20 ms scan rate, 8 comparisons per sample (DMCR = 1, DMR = 2), CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	515	—	nA
		12-bit SAR conversions, 200 ms scan rate, CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	79	—	nA
		Delta Modulation conversions, 200 ms scan rate, 8 comparisons per sample (DMCR = 1, DMR = 2), CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	57	—	nA

SPI Slave Timing

Table 4.35. SPI Slave Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCLK period [1 3 2]	t_{SCLK}		6 * $t_{HFPERCLK}$	—	—	ns
SCLK high time[1 3 2]	t_{SCLK_HI}		2.5 * $t_{HFPERCLK}$	—	—	ns
SCLK low time[1 3 2]	t_{SCLK_LO}		2.5 * $t_{HFPERCLK}$	—	—	ns
CS active to MISO [1 3]	$t_{CS\_ACT\_MI}$		24	—	69	ns
CS disable to MISO [1 3]	$t_{CS\_DIS\_MI}$		19	—	175	ns
MOSI setup time [1 3]	t_{SU_MO}		7	—	—	ns
MOSI hold time [1 3 2]	t_{H_MO}		6	—	—	ns
SCLK to MISO [1 3 2]	t_{SCLK_MI}		16 + 1.5 * $t_{HFPERCLK}$	—	43 + 2.5 * $t_{HFPERCLK}$	ns

Note:

1. Applies for both CLKPHA = 0 and CLKPHA = 1 (figure only shows CLKPHA = 0).
2. $t_{HFPERCLK}$ is one period of the selected HFPERCLK.
3. Measurement done with 8 pF output loading at 10% and 90% of V_{DD} (figure shows 50% of V_{DD}).

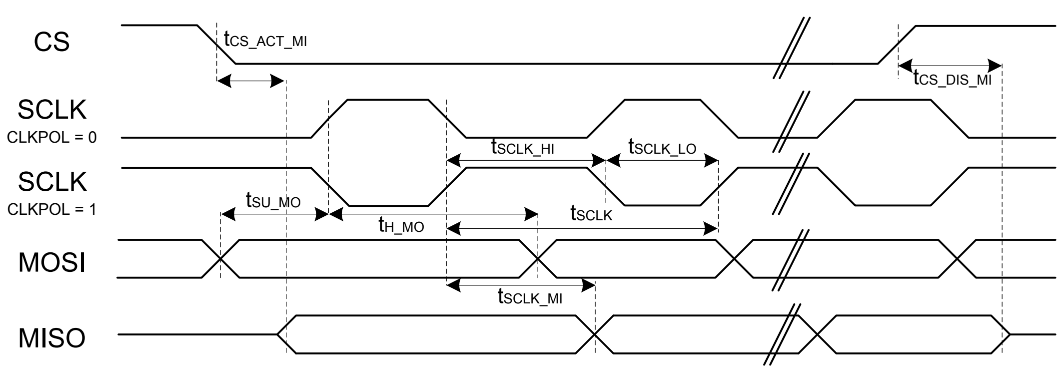

Figure 4.2. SPI Slave Timing Diagram

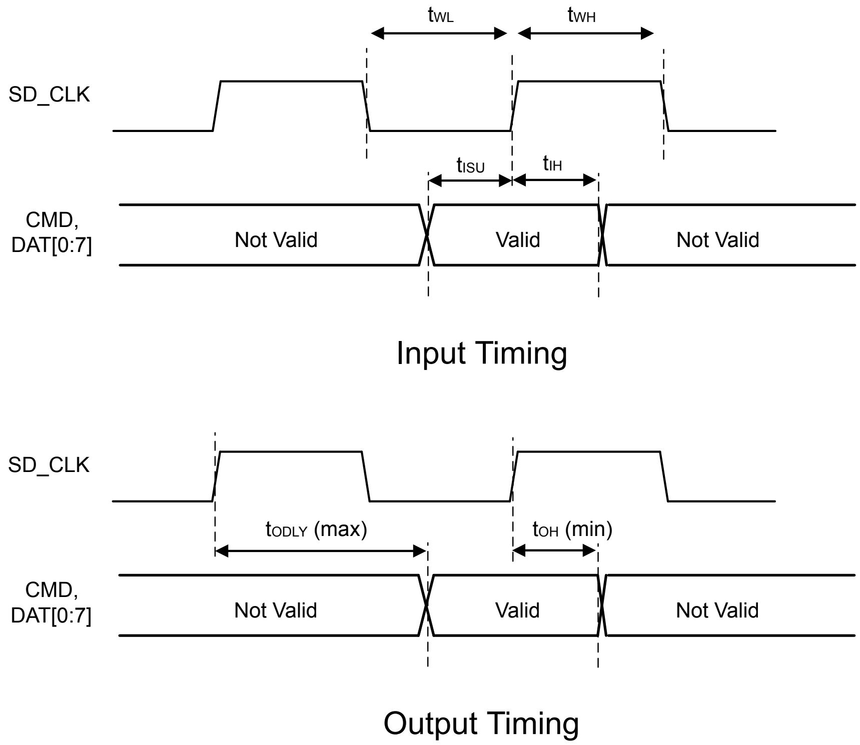

Figure 4.14. SDIO HS Mode Timing

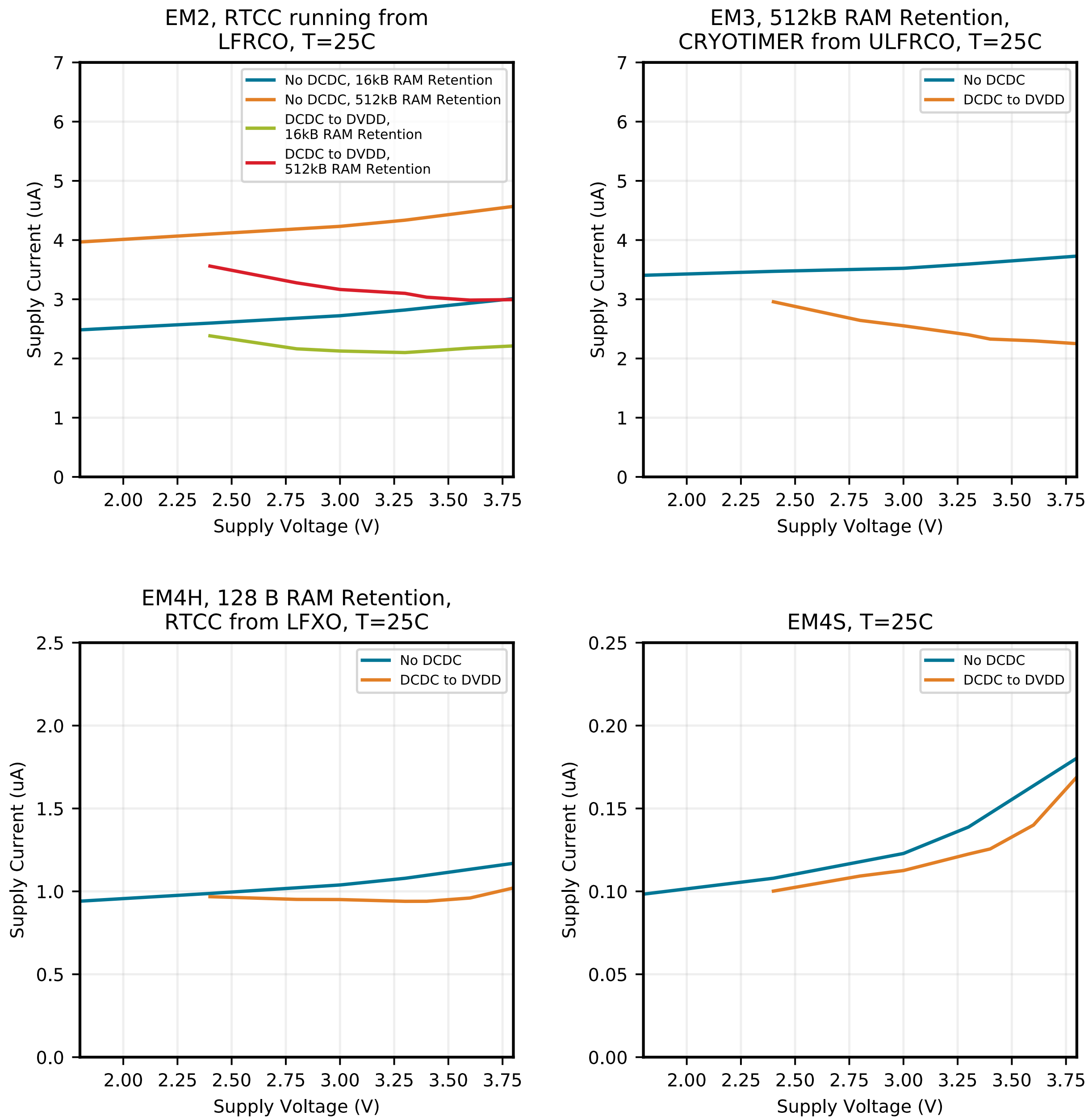

Figure 4.28. EM2, EM3, EM4H and EM4S Typical Supply Current vs. Supply

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description

Note:
1. GPIO with 5V tolerance are indicated by (5V).
2. The pins PD13, PD14, and PD15 will not be 5V tolerant on all future devices. In order to preserve upgrade options with full hardware compatibility, do not use these pins with 5V domains.

5.4 EFM32GG11B5xx in BGA120 Device Pinout

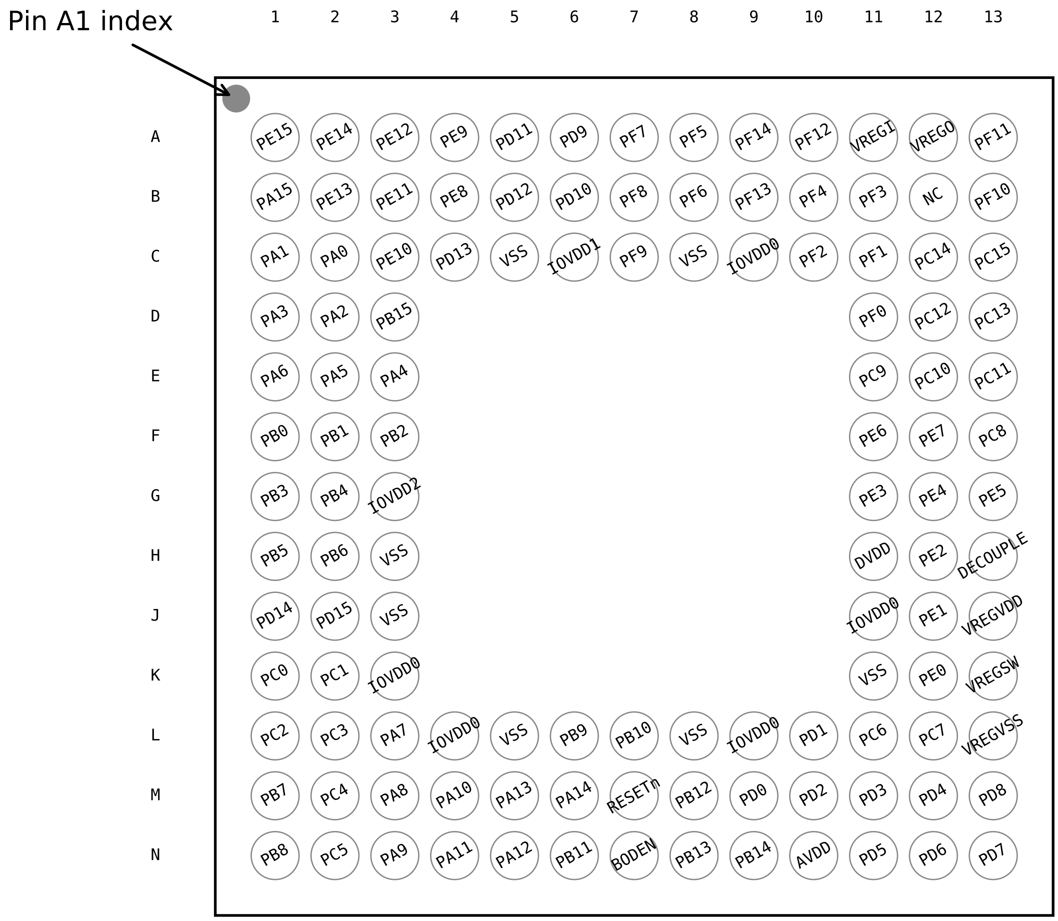

Figure 5.4. EFM32GG11B5xx in BGA120 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see 5.20 GPIO Functionality Table or 5.21 Alternate Functionality Overview.

Table 5.4. EFM32GG11B5xx in BGA120 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PE15	A1	GPIO	PE14	A2	GPIO
PE12	A3	GPIO	PE9	A4	GPIO
PD11	A5	GPIO	PD9	A6	GPIO
PF7	A7	GPIO	PF5	A8	GPIO
PF14	A9	GPIO (5V)	PF12	A10	GPIO
VREGI	A11	Input to 5 V regulator.	VREGO	A12	Decoupling for 5 V regulator and regulator output. Power for USB PHY in USB-enabled OPNs

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PD8	H8	GPIO	PD5	H9	GPIO
PD6	H10	GPIO	PD7	H11	GPIO
PC1	J1	GPIO (5V)	PC3	J2	GPIO (5V)
PD15	J3	GPIO (5V)	PA12	J4	GPIO (5V)
PA9	J5	GPIO	PA10	J6	GPIO
PB9	J7	GPIO (5V)	PB10	J8	GPIO (5V)
PD2	J9	GPIO (5V)	PD3	J10	GPIO
PD4	J11	GPIO	PB7	K1	GPIO
PC4	K2	GPIO	PA13	K3	GPIO (5V)
PA11	K5	GPIO	RESETn	K6	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
AVDD	K8 K9 L10	Analog power supply.	PD1	K11	GPIO
PB8	L1	GPIO	PC5	L2	GPIO
PA14	L3	GPIO	PB11	L5	GPIO
PB12	L6	GPIO	PB13	L8	GPIO
PB14	L9	GPIO	PD0	L11	GPIO (5V)

Note:

1. GPIO with 5V tolerance are indicated by (5V).
2. The pins PD13, PD14, and PD15 will not be 5V tolerant on all future devices. In order to preserve upgrade options with full hardware compatibility, do not use these pins with 5V domains.

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
LES_ALTEX6	0: PE12		LESENSE alternate excite output 6.
LES_ALTEX7	0: PE13		LESENSE alternate excite output 7.
LES_CH0	0: PC0		LESENSE channel 0.
LES_CH1	0: PC1		LESENSE channel 1.
LES_CH2	0: PC2		LESENSE channel 2.
LES_CH3	0: PC3		LESENSE channel 3.
LES_CH4	0: PC4		LESENSE channel 4.
LES_CH5	0: PC5		LESENSE channel 5.
LES_CH6	0: PC6		LESENSE channel 6.
LES_CH7	0: PC7		LESENSE channel 7.
LES_CH8	0: PC8		LESENSE channel 8.
LES_CH9	0: PC9		LESENSE channel 9.
LES_CH10	0: PC10		LESENSE channel 10.

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
QSPI0_DQ7	0: PE11 1: PB6 2: PG8		Quad SPI 0 Data 7.
QSPI0_DQS	0: PF9 1: PE15 2: PG11		Quad SPI 0 Data S.
QSPI0_SCLK	0: PF6 1: PE14 2: PG0		Quad SPI 0 Serial Clock.
SDIO_CD	0: PF8 1: PC4 2: PA6 3: PB10		SDIO Card Detect.
SDIO_CLK	0: PE13 1: PE14		SDIO Serial Clock.
SDIO_CMD	0: PE12 1: PE15		SDIO Command.
SDIO_DAT0	0: PE11 1: PA0		SDIO Data 0.
SDIO_DAT1	0: PE10 1: PA1		SDIO Data 1.
SDIO_DAT2	0: PE9 1: PA2		SDIO Data 2.
SDIO_DAT3	0: PE8 1: PA3		SDIO Data 3.
SDIO_DAT4	0: PD12 1: PA4		SDIO Data 4.
SDIO_DAT5	0: PD11 1: PA5		SDIO Data 5.
SDIO_DAT6	0: PD10 1: PB3		SDIO Data 6.

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
U0_TX	0: PF6 1: PE0 2: PA3 3: PC14	4: PC4 5: PF1 6: PD7	UART0 Transmit output. Also used as receive input in half duplex communication.
U1_CTS	0: PC14 1: PF9 2: PB11 3: PE4	4: PC4 5: PH13	UART1 Clear To Send hardware flow control input.
U1_RTS	0: PC15 1: PF8 2: PB12 3: PE5	4: PC5 5: PH14	UART1 Request To Send hardware flow control output.
U1_RX	0: PC13 1: PF11 2: PB10 3: PE3	4: PE13 5: PH12	UART1 Receive input.
U1_TX	0: PC12 1: PF10 2: PB9 3: PE2	4: PE12 5: PH11	UART1 Transmit output. Also used as receive input in half duplex communication.
US0_CLK	0: PE12 1: PE5 2: PC9 3: PC15	4: PB13 5: PA12 6: PG14	USART0 clock input / output.
US0_CS	0: PE13 1: PE4 2: PC8 3: PC14	4: PB14 5: PA13 6: PG15	USART0 chip select input / output.
US0_CTS	0: PE14 1: PE3 2: PC7 3: PC13	4: PB6 5: PB11 6: PH0	USART0 Clear To Send hardware flow control input.
US0_RTS	0: PE15 1: PE2 2: PC6 3: PC12	4: PB5 5: PD6 6: PH1	USART0 Request To Send hardware flow control output.
US0_RX	0: PE11 1: PE6 2: PC10 3: PE12	4: PB8 5: PC1 6: PG13	USART0 Asynchronous Receive. USART0 Synchronous mode Master Input / Slave Output (MISO).
US0_TX	0: PE10 1: PE7 2: PC11 3: PE13	4: PB7 5: PC0 6: PG12	USART0 Asynchronous Transmit. Also used as receive input in half duplex communication. USART0 Synchronous mode Master Output / Slave Input (MOSI).
US1_CLK	0: PB7 1: PD2 2: PF0 3: PC15	4: PC3 5: PB11 6: PE5	USART1 clock input / output.
US1_CS	0: PB8 1: PD3 2: PF1 3: PC14	4: PC0 5: PE4 6: PB2	USART1 chip select input / output.

6.2 BGA192 PCB Land Pattern

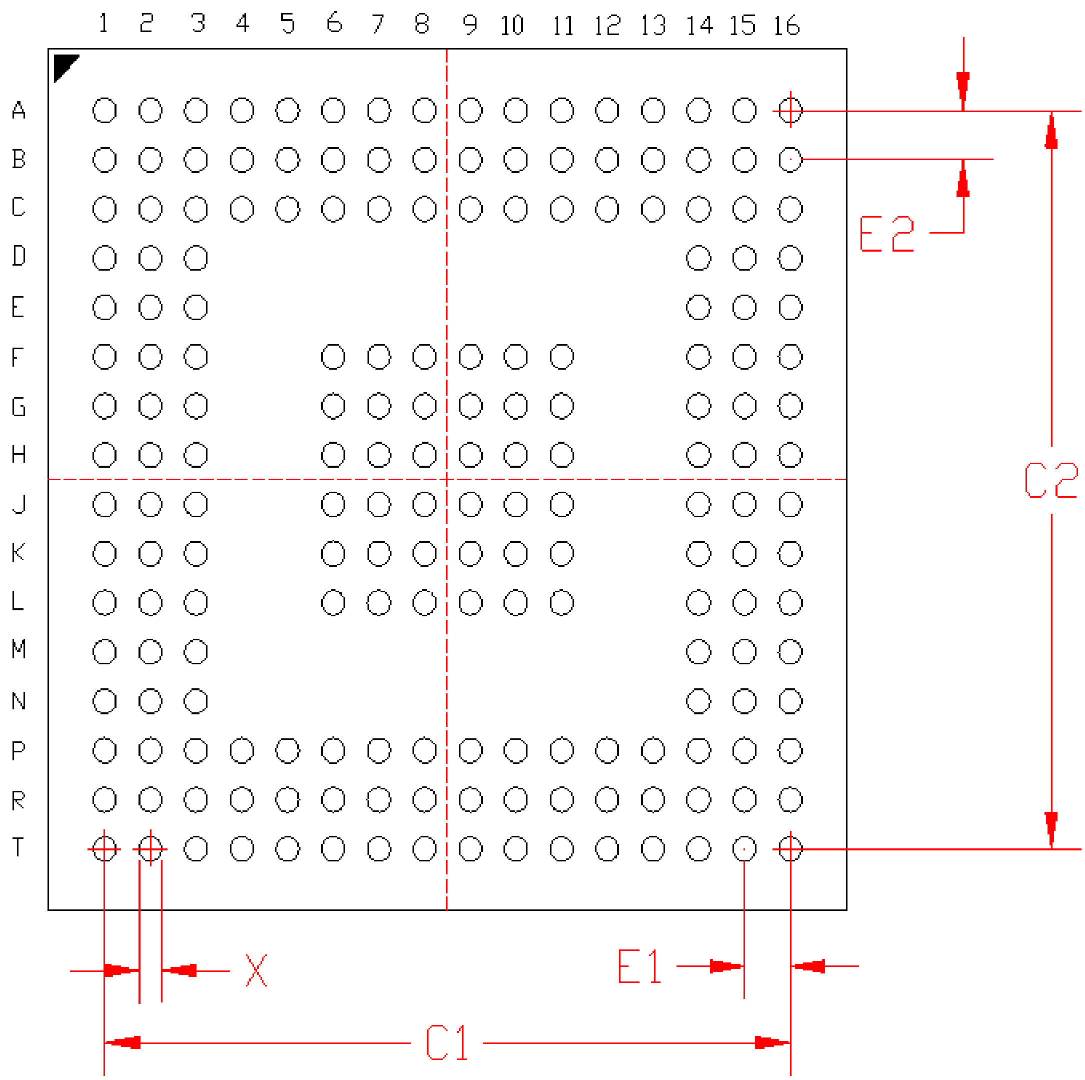

Figure 6.2. BGA192 PCB Land Pattern Drawing

8.3 BGA120 Package Marking

Figure 8.3. BGA120 Package Marking

The package marking consists of:

- PPPPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code. The first letter is the device revision.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.

10.2 TQFP100 PCB Land Pattern

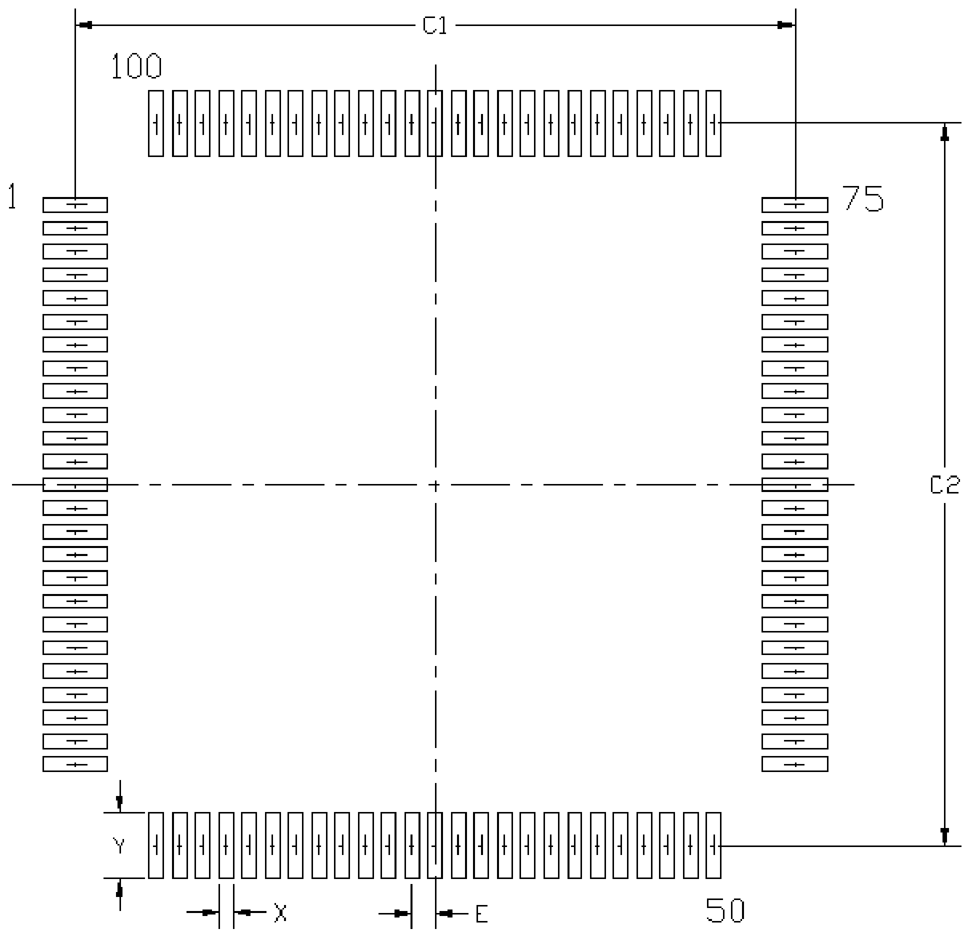

Figure 10.2. TQFP100 PCB Land Pattern Drawing

11. TQFP64 Package Specifications

11.1 TQFP64 Package Dimensions

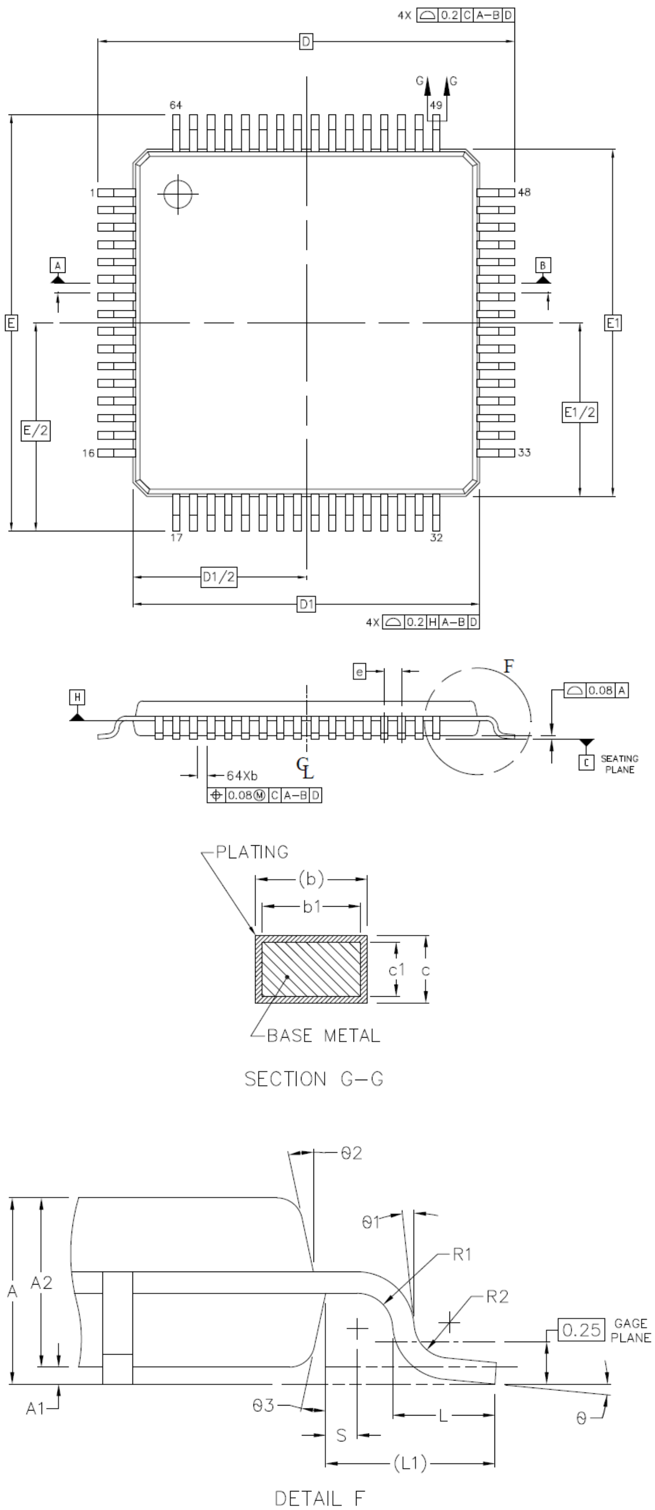

Figure 11.1. TQFP64 Package Drawing

12.2 QFN64 PCB Land Pattern

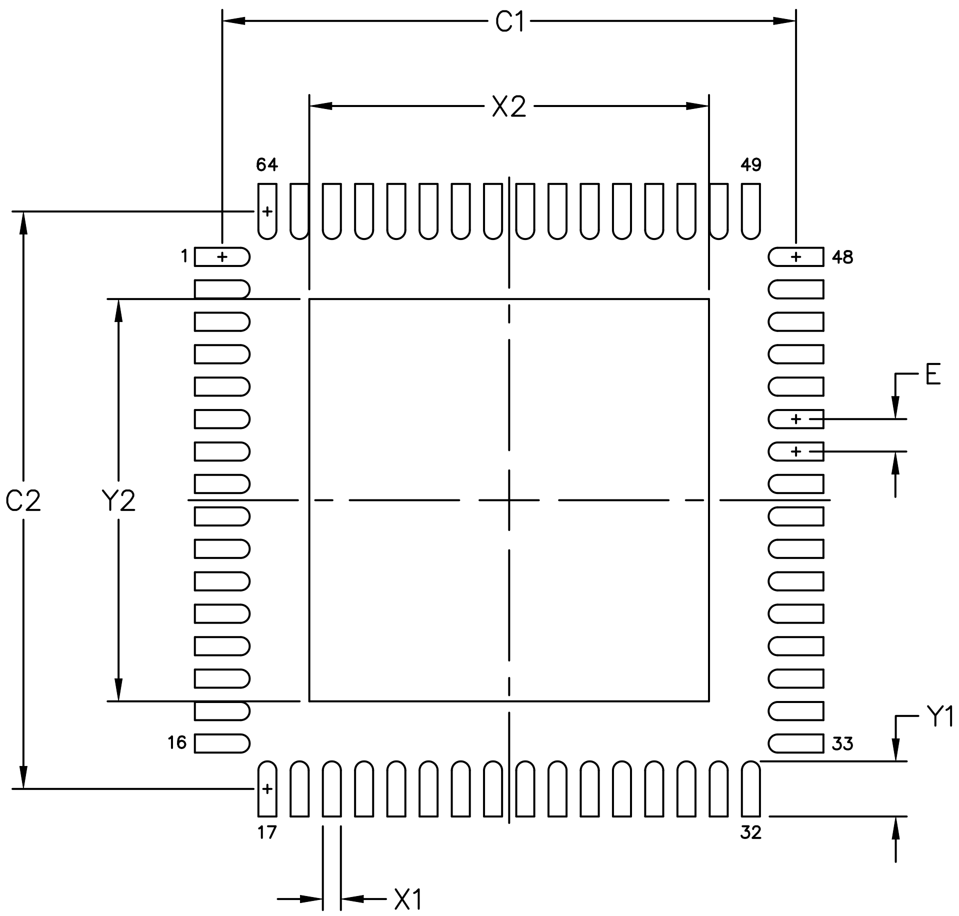

Figure 12.2. QFN64 PCB Land Pattern Drawing